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BOX 5120, LCD MERIVALE  
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PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B  
Type: Semiconductor Device Tester  
S.N.: 12420 (repair)  
Date: November 21, 2018

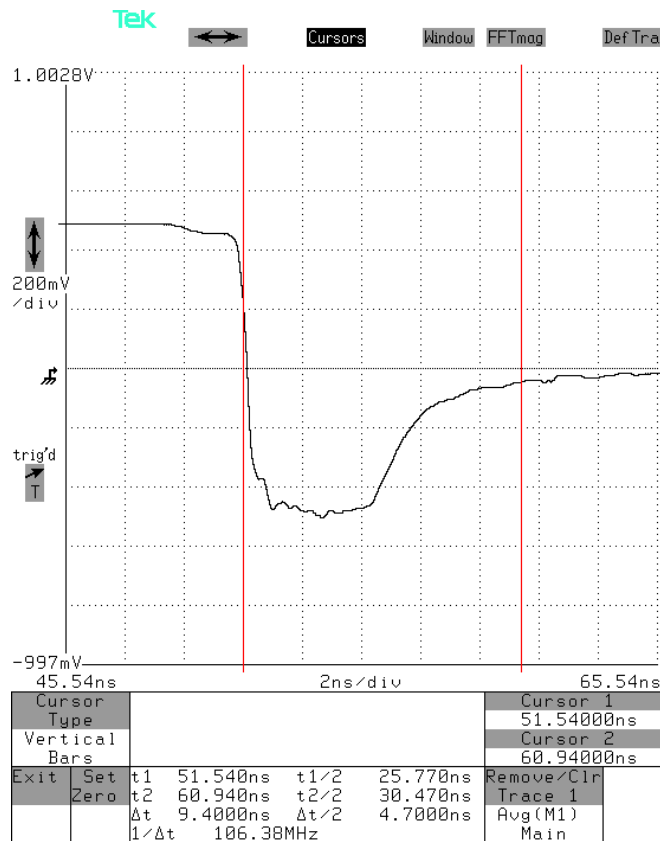
Output Amplitude: to +100 mA, -100 mA  
Pulse Width (FWHM): 200 ns  
Switching Time,  
+ to -, 10%-90%: ≤ 300 ps (at mainframe)  
PRF: 1 - 10 kHz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

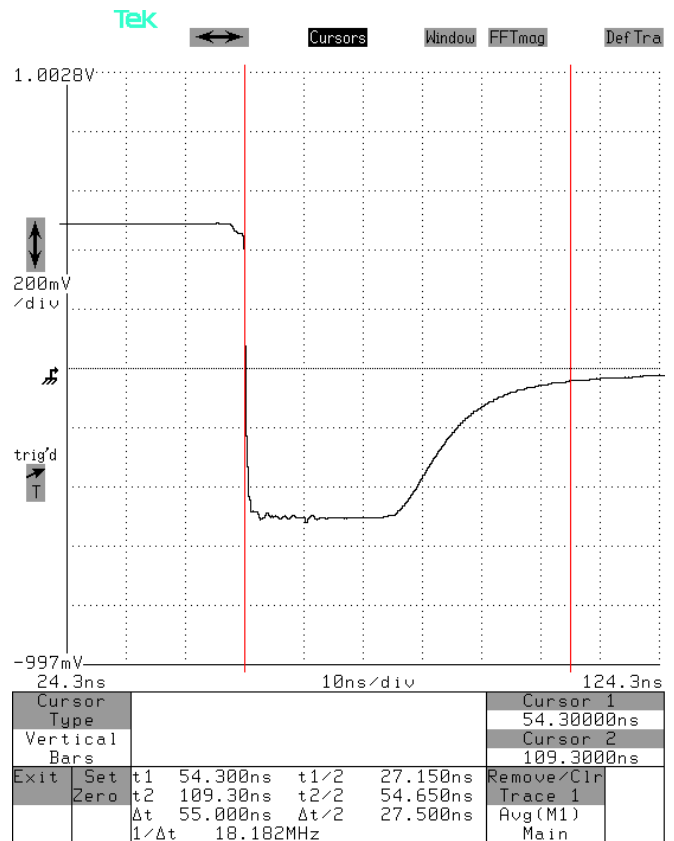
With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:



I<sub>F</sub> = +100 mA, I<sub>R</sub> = - 100 mA

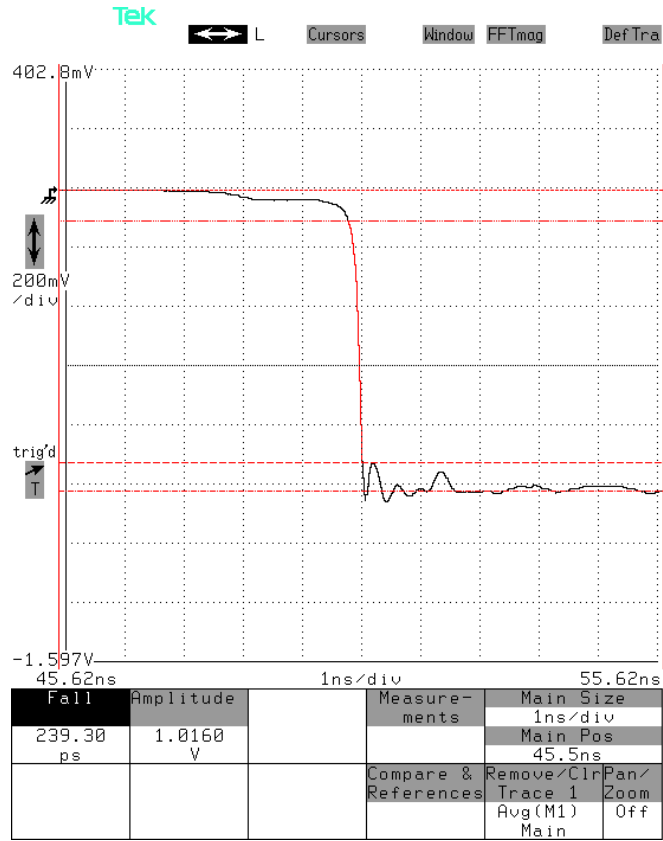
Measured t<sub>RR</sub> = 9.4 ns.



I<sub>F</sub> = +100 mA, I<sub>R</sub> = - 100 mA

Measured t<sub>RR</sub> = 55 ns.

Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 2 ns/div):



Shows a 10%-90% transition time of 239.3 ps.